

| Search Notes<br> | Application/Control No. | Applicant(s)/Patent under Reexamination |
|--|-------------------------|---|
|  | 10/710,693              | BHOOSHAN ET AL.                         |
|  | Examiner                | Art Unit                                |
|  | Phallaka Kik            | 2825                                    |

**SEARCHED**

| INTERFERENCE SEARCHED |          |      |          |
|-----------------------|----------|------|----------|
| Class                 | Subclass | Date | Examiner |
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| SEARCH NOTES<br>(INCLUDING SEARCH STRATEGY)                                    |           |      |
|--|-----------|------|
|  | DATE      | EXMR |
| BRS (EAST)<br>-USPAT, USPGPUB<br>Clis/Sub searched:<br>716/1-18 (see attached) | 6/12/2006 | PK   |
| -EPO, JPO, IBM TDB, Derwent<br>(see attached)                                  | 6/12/2006 | PK   |
| IEEE/IEEE Xplore<br>(see attached)   | 6/12/2006 | PK   |
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